Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOS)

2SK2466

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4 V gate drive

• Low drain–source ON resistance : RDS (ON) = 34 m Ω (typ.)

• High forward transfer admittance : $|Y_{fs}| = 30 \text{ S (typ.)}$

• Low leakage current $I_{DSS} = 100 \,\mu\text{A} \,(\text{max}) \,(V_{DS} = 100 \,\text{V})$

• Enhancement-mode : $V_{th} = 0.8 \sim 2.0 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	100	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	100	٧	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	ΙD	30	А	
Drain current	Pulse (Note 1)	I_{DP}	120		
Drain power dissipatio	n (Tc = 25°C)	P_{D}	40	W	
Single pulse avalanche energy (Note 2)		E _{AS}	293	mJ	
Avalanche current		I _{AR}	30	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	4	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Weight: 1.9 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.125	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 525 μ H, R_{G} = 25 Ω , I_{AR} = 30 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device.

Please handle with caution.



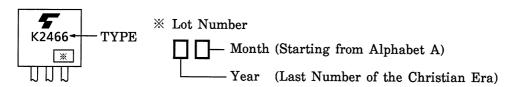
Electrical Characteristics (Ta = 25°C)

Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold v	/oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		D	V _{GS} = 4 V, I _D = 15 A	_	40	70	- mΩ
		R _{DS (ON)}	V _{GS} = 10 V, I _D = 15 A	_	34	46	
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 15 A	13	30	_	S
Input capacitano	ce	C _{iss}		_	3250	_	
Reverse transfe	r capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	230	_	pF
Output capacitance		C _{oss}		_	520	_	
Switching time	Rise time	t _r	V_{GS} V_{OV} V_{OUT} V_{OUT} V_{OUT}	_	33	_	
	Turn-on time	t _{on}	$^{\circ}$	_	60	_	ne
	Fall time	t _f		_	95	_	ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\mathbf{W}} = 10 \ \mu s$	_	230	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	68	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		46	_	nC
Gate-drain ("miller") charge		Q _{gd}			22	_	

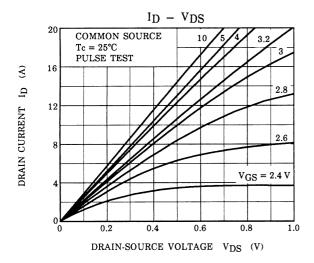
Source-Drain Ratings and Characteristics (Ta = 25°C)

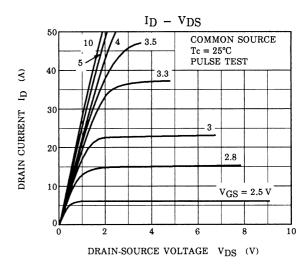
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	30	Α
Pulse drain reverse current (Note 1)	I _{DRP}	-	_	_	120	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 30 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 30 A, V _{GS} = 0 V	1	120	1	ns
Reverse recovery charge	Q _{rr}	dI_{DR} / $dt = 50 A / \mu s$	_	280	_	μC

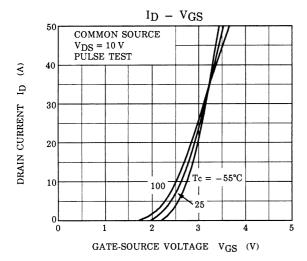
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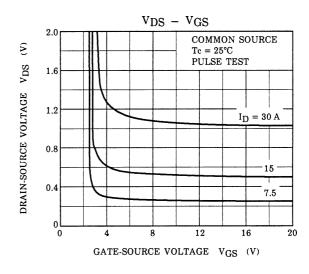


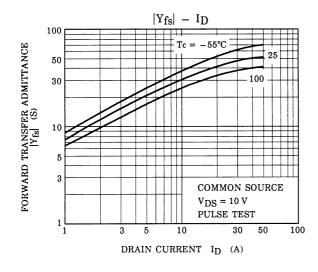
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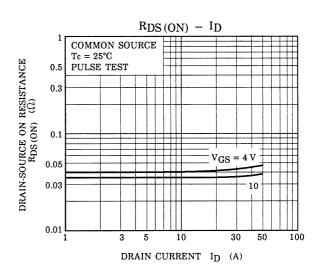




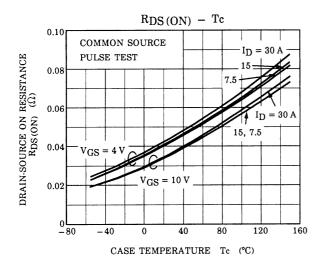


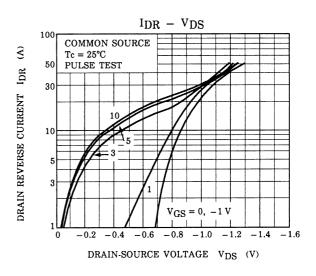


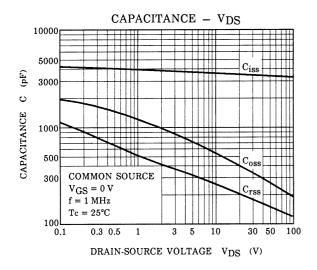


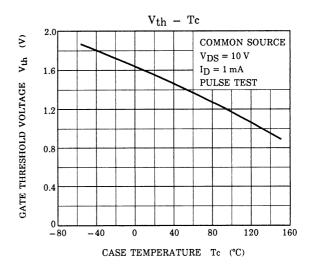


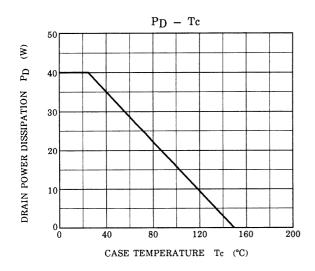
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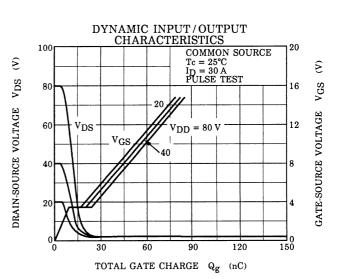




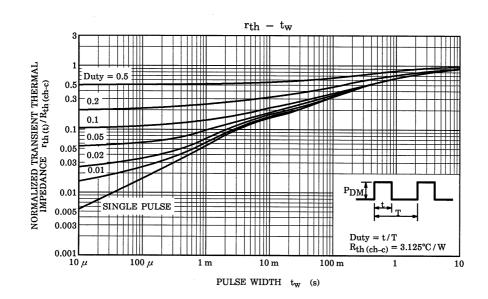


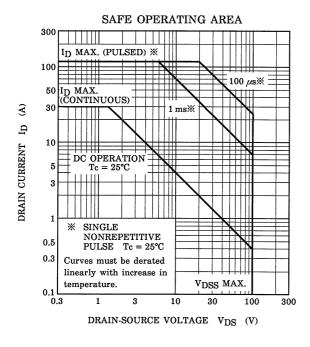


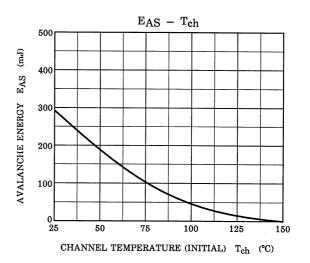


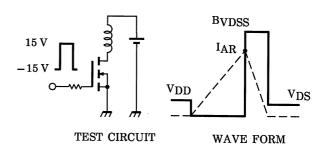


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$$RG = 25 \Omega$$

 $V_{DD} = 25 V$, $L = 525 \mu H$

EAS =
$$\frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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